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| Application/Control No. | Applicant(s)/Patent under Reexamination |
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| 09/911,375 | FURUKAWA, HIDEYUKI |
| Examiner | Art Unit |
| Esaw T. Abraham | 2133 |

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| Class | Subclass | Date | Examiner | |
| . 714 | 763, 25, 48 | 5/19/2005 | EA | |
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| SEARCH NOT (INCLUDING SEARCH | |) |
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| | DATE | EXMR |
| East, NPL (IEEE search), inventor's search was conducted for double patenting. No double patenting issue was found. | 5/19/2005 | EA |
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